U.S. PATENT DOCUMENTS

Examiner Initials		Document No.	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Documents	
D.D./	AA	4,327,387	04-27-1982	Plotto	
	AB	4,863,809	09-05-1989	Brar et al.	
	AC	4,992,300	02-12-1991	Ogawa et al.	
	AD	5,271,802	12-21-1993	Chang et al.	
	AE	5,425,988	06-20-1995	Ogawa et al.	
	AF	6,479,111 B2	11-12-2002	Dykes et al.	
	AG	6,586,069 B2	07-01-2003	Dykes et al.	
	АН	6,743,481 B2	06-01-2004	Hoehn et al.	
	Al	6,822,833 B2	11-23-2004	Yang et al.	
	AJ	2004/0156145 A1	08-12-2004	Koishi	
$\overline{\Psi}$	AK	20014/0223256 A1	11-11-2004	Feng et al.	
D.D./	AL	2004/0223262 A1	11-11-2004	Feng et al.	

FOREIGN PATENT DOCUMENTS

		Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Documents	Translation Yes No
/D.D./	АМ	JP 09120525	05-06-1997	Momose	No
/D.D./	AN	JP 2001-043650	02-16-2001	Furuichi et al.	No
/D.D./	AO	JP 2001-297410	10-26-2001	Nasu et al.	No

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AP				
AO				
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